Scott D Findlay

List of Publications by Year
in descending order

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164 papers	7,304 citations	61984 43 h-index	56724 83 g-index
168 all docs	168 docs citations	168 times ranked	5140 citing authors

#	Article	IF	Citations
1	Factors limiting quantitative phase retrieval in atomic-resolution differential phase contrast scanning transmission electron microscopy using a segmented detector. Ultramicroscopy, 2022, 233, 113457.	1.9	5
2	Real-space visualization of intrinsic magnetic fields of an antiferromagnet. Nature, 2022, 602, 234-239.	27.8	41
3	Linear imaging theory for differential phase contrast and other phase imaging modes in scanning transmission electron microscopy. Ultramicroscopy, 2022, , 113580.	1.9	3
4	A Three-Dimensional Reconstruction Algorithm for Scanning Transmission Electron Microscopy Data from a Single Sample Orientation. Microscopy and Microanalysis, 2022, 28, 1632-1640.	0.4	6
5	Optimizing Experimental Conditions for Accurate Quantitative Energy-Dispersive X-ray Analysis of Interfaces at the Atomic Scale. Microscopy and Microanalysis, 2021, 27, 528-542.	0.4	6
6	Phase-contrast imaging of multiply-scattering extended objects at atomic resolution by reconstruction of the scattering matrix. Physical Review Research, 2021, 3, .	3.6	11
7	Scattering Matrix Determination in Crystalline Materials from 4D Scanning Transmission Electron Microscopy at a Single Defocus Value. Microscopy and Microanalysis, 2021, 27, 744-757.	0.4	5
8	Suppressing dynamical diffraction artefacts in differential phase contrast scanning transmission electron microscopy of long-range electromagnetic fields via precession. Ultramicroscopy, 2020, 219, 113097.	1.9	16
9	Angular dependence of fast-electron scattering from materials. Physical Review B, 2020, 101, .	3.2	16
10	Inelastic Scattering in Electron Backscatter Diffraction and Electron Channeling Contrast Imaging. Microscopy and Microanalysis, 2020, 26, 1147-1157.	0.4	3
11	Pushing the Limits of Absolute Scale Energy Dispersive X-ray Quantification. Microscopy and Microanalysis, 2019, 25, 968-969.	0.4	0
12	Rapid Simulation of Elemental Maps in Core-Loss Electron Energy Loss Spectroscopy. Microscopy and Microanalysis, 2019, 25, 574-575.	0.4	1
13	Structure Retrieval of Strongly Scattering Materials in the Transmission Electron Microscope. Microscopy and Microanalysis, 2019, 25, 76-77.	0.4	0
14	Imaging Low Z Materials in Crystalline Environments Via Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2019, 25, 1732-1733.	0.4	2
15	Atomic resolution electron microscopy in a magnetic field free environment. Nature Communications, 2019, 10, 2308.	12.8	50
16	High contrast at low dose using a single, defocussed transmission electron micrograph. Micron, 2019, 124, 102701.	2.2	6
17	Large angle illumination enabling accurate structure reconstruction from thick samples in scanning transmission electron microscopy. Ultramicroscopy, 2019, 197, 112-121.	1.9	12
18	Electric Field Imaging at Atomic Resolution by DPC STEM. Materia Japan, 2019, 58, 104-104.	0.1	0

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19	Probing the limits of the rigid-intensity-shift model in differential-phase-contrast scanning transmission electron microscopy. Physical Review A, 2018, 97, .	2.5	20
20	Understanding electron magnetic circular dichroism in a transition potential approach. Physical Review B, 2018, 97, .	3.2	3
21	A menu of electron probes for optimising information from scanning transmission electron microscopy. Ultramicroscopy, 2018, 184, 143-155.	1.9	10
22	Structure Retrieval at Atomic Resolution in the Presence of Multiple Scattering of the Electron Probe. Physical Review Letters, 2018, 121, 266102.	7.8	29
23	Direct electric field imaging of graphene defects. Nature Communications, 2018, 9, 3878.	12.8	74
24	Probe Shaping for Quantitative DPC-STEM Using Segmented Detectors. Microscopy and Microanalysis, 2018, 24, 916-917.	0.4	0
25	A quantum mechanical exploration of phonon energy-loss spectroscopy using electrons in the aloof beam geometry. Microscopy (Oxford, England), 2018, 67, i24-i29.	1.5	11
26	Probing the Internal Atomic Charge Density Distributions in Real Space. ACS Nano, 2018, 12, 8875-8881.	14.6	43
27	The atomic structure of polar and non-polar InGaN quantum wells and the green gap problem. Ultramicroscopy, 2017, 176, 93-98.	1.9	24
28	Accuracy and precision of thickness determination from position-averaged convergent beam electron diffraction patterns using a single-parameter metric. Ultramicroscopy, 2017, 181, 86-96.	1.9	8
29	Absolute-Scale Comparison with Simulation for Quantitative Energy-Dispersive X-Ray Spectroscopy in Atomic-Resolution Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2017, 23, 388-389.	0.4	1
30	Quantitative electric field mapping in thin specimens using a segmented detector: Revisiting the transfer function for differential phase contrast. Ultramicroscopy, 2017, 182, 258-263.	1.9	36
31	Probing the effect of electron channelling on atomic resolution energy dispersive X-ray quantification. Ultramicroscopy, 2017, 182, 264-275.	1.9	22
32	Three-Dimensional Point Defect Imaging by Large-angle Illumination STEM. Microscopy and Microanalysis, 2017, 23, 424-425.	0.4	1
33	Measuring nanometre-scale electric fields in scanning transmission electron microscopy using segmented detectors. Ultramicroscopy, 2017, 182, 169-178.	1.9	20
34	Direct Visualization of Local Electromagnetic Field Structures by Scanning Transmission Electron Microscopy. Accounts of Chemical Research, 2017, 50, 1502-1512.	15.6	72
35	Composition measurement in substitutionally disordered materials by atomic resolution energy dispersive X-ray spectroscopy in scanning transmission electron microscopy. Ultramicroscopy, 2017, 176, 52-62.	1.9	15
36	Annular Bright-Field Scanning Transmission Electron Microscopy: Direct and Robust Atomic-Resolution Imaging of Light Elements in Crystalline Materials. Microscopy Today, 2017, 25, 36-41.	0.3	7

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37	Probing the Effects of Electron Channelling on EDX Quantification. Microscopy and Microanalysis, 2017, 23, 392-393.	0.4	0
38	Quantitative Specimen Electric Potential Maps Using Segmented and Pixel Detectors in Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2017, 23, 442-443.	0.4	1
39	Understanding Imaging and Energy-loss Spectra Due to Phonon Excitation. Microscopy and Microanalysis, 2017, 23, 1536-1537.	0.4	0
40	Electric field imaging of single atoms. Nature Communications, 2017, 8, 15631.	12.8	144
41	ABF-STEM Characterization of the {1100} Stacking Fault in Alumina. Materia Japan, 2016, 55, 610-610.	0.1	0
42	Direct Electromagnetic Structure Observation by Aberration-corrected Differential Phase Contrast Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2016, 22, 906-907.	0.4	1
43	Making every electron count: materials characterization by quantitative analytical scanning transmission electron microscopy. Microscopy and Microanalysis, 2016, 22, 1430-1431.	0.4	0
44	Quantitative Atomic Resolution Differential Phase Contrast Imaging Using a Segmented Area All Field Detector. Microscopy and Microanalysis, 2016, 22, 504-505.	0.4	1
45	Facilitating Quantitative Analysis of Atomic Scale 4D STEM Datasets. Microscopy and Microanalysis, 2016, 22, 474-475.	0.4	1
46	Low magnification differential phase contrast imaging of electric fields in crystals with fine electron probes. Ultramicroscopy, 2016, 169, 69-79.	1.9	9
47	Single atom visibility in STEM optical depth sectioning. Applied Physics Letters, 2016, 109, .	3.3	40
48	The microstructure of non-polar a-plane (112Â¯0) InGaN quantum wells. Journal of Applied Physics, 2016, 119, .	2.5	22
49	Quantitative atomic resolution elemental mapping via absolute-scale energy dispersive X-ray spectroscopy. Ultramicroscopy, 2016, 168, 7-16.	1.9	49
50	Practical aspects of diffractive imaging using an atomic-scale coherent electron probe. Ultramicroscopy, 2016, 169, 107-121.	1.9	27
51	Direct visualization of lithium via annular bright field scanning transmission electron microscopy: a review. Microscopy (Oxford, England), 2016, 66, 3-14.	1.5	20
52	Influence of experimental conditions on atom column visibility in energy dispersive X-ray spectroscopy. Ultramicroscopy, 2016, 171, 1-7.	1.9	10
53	Structure retrieval with fast electrons using segmented detectors. Physical Review B, 2016, 93, .	3.2	24
54	Atomic structure characterization of stacking faults on the {11Â¯00} plane in Î±-alumina by scanning transmission electron microscopy. AIP Conference Proceedings, 2016, , .	0.4	4

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55	Complex Point Defect Structure in Cubic Boron Nitride. Materia Japan, 2016, 55, 609-609.	0.1	0
56	Accurate Nanoscale Crystallography in Real-Space Using Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2015, 21, 946-952.	0.4	35
57	Towards quantitative, atomic-resolution reconstruction of the electrostatic potential via differential phase contrast using electrons. Ultramicroscopy, 2015, 159, 124-137.	1.9	118
58	Atomic resolution imaging using electron energy-loss phonon spectroscopy. Physical Review B, 2015, 91, .	3.2	18
59	Imaging of built-in electric field at a p-n junction by scanning transmission electron microscopy. Scientific Reports, 2015, 5, 10040.	3.3	119
60	Stabilisation of Fe2O3-rich Perovskite Nanophase in Epitaxial Rare-earth Doped BiFeO3 Films. Scientific Reports, 2015, 5, 13066.	3.3	9
61	Highly Accurate Real Space Nanometrology Using Revolving Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2015, 21, 2245-2246.	0.4	0
62	Annular Bright Field Scanning Transmission Electron Microscopy - Direct and Robust Atomic-Resolution Imaging of Light Elements in Crystalline Materials. Microscopy and Microanalysis, 2015, 21, 1939-1940.	0.4	0
63	Influence of Convergence Angle and Finite Effective Source Size for Quantitative Atomic Resolution EDXS. Microscopy and Microanalysis, 2015, 21, 1093-1094.	0.4	0
64	Quantitative Electron Microscopy and the Application by Single Electron Signals. Microscopy and Microanalysis, 2015, 21, 1449-1450.	0.4	0
65	Dopant Quantification by Atomic-scale Energy Dispersive X-ray Analysis. Microscopy and Microanalysis, 2015, 21, 819-820.	0.4	0
66	Absolute-Scale Quantitative Energy Dispersive X-ray Analysis in Aberration-Corrected Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2015, 21, 1079-1080.	0.4	3
67	Simulating Inelastic Scattering in Scanning Transmission Electron Microscopy using Î¼STEM. Microscopy and Microanalysis, 2015, 21, 1885-1886.	0.4	0
68	Modelling the inelastic scattering of fast electrons. Ultramicroscopy, 2015, 151, 11-22.	1.9	171
69	Energy dispersive X-ray analysis on an absolute scale in scanning transmission electron microscopy. Ultramicroscopy, 2015, 157, 21-26.	1.9	37
70	Enhanced light element imaging in atomic resolution scanning transmission electron microscopy. Ultramicroscopy, 2014, 136, 31-41.	1.9	40
71	Quantitative Annular Dark Field Electron Microscopy Using Single Electron Signals. Microscopy and Microanalysis, 2014, 20, 99-110.	0.4	80
72	Room-Temperature Polar Ferromagnet ScFeO₃ Transformed from a High-Pressure Orthorhombic Perovskite Phase. Journal of the American Chemical Society, 2014, 136, 15291-15299.	13.7	78

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73	Direct Observation of Dopant Atom Diffusion in a Bulk Semiconductor Crystal Enhanced by a Large Size Mismatch. Physical Review Letters, 2014, 113, 155501.	7.8	91
74	Practical Aspects of Removing the Effects of Elastic and Thermal Diffuse Scattering from Spectroscopic Data for Single Crystals. Microscopy and Microanalysis, 2014, 20, 1078-1089.	0.4	10
75	Three-Dimensional Location of a Single Dopant with Atomic Precision by Aberration-Corrected Scanning Transmission Electron Microscopy. Nano Letters, 2014, 14, 1903-1908.	9.1	89
76	The spatial coherence function in scanning transmission electron microscopy and spectroscopy. Ultramicroscopy, 2014, 146, 6-16.	1.9	19
77	Tracking Dopant Diffusion Pathways inside Bulk Materials. Microscopy and Microanalysis, 2014, 20, 50-51.	0.4	0
78	Atomic-Resolution Scanning Transmission Electron Microscopy with Segmented Annular All Field Detector. Microscopy and Microanalysis, 2014, 20, 64-65.	0.4	2
79	Quantitative EDX and EELS Elemental Mapping at Atomic Resolution. Microscopy and Microanalysis, 2014, 20, 570-571.	0.4	1
80	Polar Oxide Interface Characterization by Differential Phase Contrast STEM. Microscopy and Microanalysis, 2014, 20, 1034-1035.	0.4	0
81	Atomic Structure of Luminescent Centers in High-Efficiency Ce-doped w-AlN Single Crystal. Scientific Reports, 2014, 4, 3778.	3.3	43
82	Detecting the direction of oxygen bonding in SrTiO<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:msub><mml:mrow /><mml:mn>3</mml:mn></mml:msub></mml:math>. Physical Review B, 2013, 88, .	3.2	21
83	Detector non-uniformity in scanning transmission electron microscopy. Ultramicroscopy, 2013, 124, 52-60.	1.9	57
84	Functional Complex Point-Defect Structure in a Huge-Size-Mismatch System. Physical Review Letters, 2013, 110, 065504.	7.8	40
85	Atomic-Scale Identification of Individual Lanthanide Dopants in Optical Glass Fiber. ACS Nano, 2013, 7, 5058-5063.	14.6	27
86	Atomic structure, energetics, and chemical bonding of Y doped Î£13 grain boundaries in Î±-Al₂O₃. Philosophical Magazine, 2013, 93, 1158-1171.	1.6	10
87	Addressing Detector Non-Uniformity in Scanning Transmission Electron Microscopy. Microscopy and Microanalysis, 2013, 19, 600-601.	0.4	0
88	Real-Space Imaging of Light Elements by Annular Bright-Field Scanning Transmission Electron Microscopy. Nihon Kessho Gakkaishi, 2013, 55, 362-368.	0.0	0
89	Quantitative transmission electron microscopy at atomic resolution. Journal of Physics: Conference Series, 2012, 371, 012009.	0.4	1
90	Quantitative STEM: Experimental Methods and Applications. Journal of Physics: Conference Series, 2012, 371, 012053.	0.4	4

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91	Removing the effects of elastic and thermal scattering from electron energy-loss spectroscopic data. Applied Physics Letters, 2012, 101, .	3.3	21
92	Direct Imaging of Dopant Clustering in Metalâ€“Oxide Nanoparticles. ACS Nano, 2012, 6, 7077-7083.	14.6	32
93	Differential phase-contrast microscopy at atomic resolution. Nature Physics, 2012, 8, 611-615.	16.7	333
94	Atomic structure of a Î£3 [110]/(111) grain boundary in CeO2. Applied Physics Letters, 2012, 100, .	3.3	22
95	Simultaneous visualization of oxygen vacancies and the accompanying cation shifts in a perovskite oxide by combining annular imaging techniques. Applied Physics Letters, 2012, 100, .	3.3	18
96	Interface location by depth sectioning using a low-angle annular dark field detector. Ultramicroscopy, 2012, 113, 131-138.	1.9	11
97	Simulation and Interpretation of Images. , 2011, , 247-289.		8
98	Counting atoms with quantitative scanning transmission electron microscopy. Acta Crystallographica Section A: Foundations and Advances, 2011, 67, C105-C105.	0.3	0
99	Scanning transmission electron microscopy imaging dynamics at low accelerating voltages. Ultramicroscopy, 2011, 111, 999-1013.	1.9	6
100	Prospects for lithium imaging using annular bright field scanning transmission electron microscopy: A theoretical study. Ultramicroscopy, 2011, 111, 1144-1154.	1.9	38
101	The effect of vacancies on the annular dark field image contrast of grain boundaries: A SrTiO3 case study. Ultramicroscopy, 2011, 111, 1531-1539.	1.9	9
102	Thermal diffuse scattering in transmission electron microscopy. Ultramicroscopy, 2011, 111, 1670-1680.	1.9	30
103	Oxygenâ€Vacancy Ordering at Surfaces of Lithium Manganese(III,IV) Oxide Spinel Nanoparticles. Angewandte Chemie - International Edition, 2011, 50, 3053-3057.	13.8	127
104	Direct oxygen imaging within a ceramic interface, with some observations upon the dark contrast at the grain boundary. Ultramicroscopy, 2011, 111, 285-289.	1.9	42
105	Real-time direct observation of Li in LiCoO2 cathode material. Applied Physics Letters, 2011, 98, .	3.3	61
106	Direct Imaging of Single Dopant Atoms in a Buried Crystalline Interface by Scanning Transmission Electron Microscopy. Journal of the Vacuum Society of Japan, 2011, 54, 270-274.	0.3	0
107	Modelling thermal scattering and solving structures usingZ-contrast imaging. Acta Crystallographica Section A: Foundations and Advances, 2011, 67, C155-C156.	0.3	0
108	Direct Imaging of Hydrogen within a Crystalline Environment. Applied Physics Express, 2010, 3, 116603.	2.4	108

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109	Atomic Structures and Properties of Ceramic Interfaces â€“Combination of Cs-Corrected STEM and First Principles Calculations. Microscopy and Microanalysis, 2010, 16, 1466-1467.	0.4	0
110	Image Contrast in Aberration-Corrected Scanning Confocal Electron Microscopy. Advances in Imaging and Electron Physics, 2010, 162, 45-76.	0.2	11
111	Position averaged convergent beam electron diffraction: Theory and applications. Ultramicroscopy, 2010, 110, 118-125.	1.9	184
112	Energy-filtered transmission electron microscopy based on inner-shell ionization. Ultramicroscopy, 2010, 110, 981-990.	1.9	14
113	Dynamics of annular bright field imaging in scanning transmission electron microscopy. Ultramicroscopy, 2010, 110, 903-923.	1.9	373
114	New area detector for atomic-resolution scanning transmission electron microscopy. Journal of Electron Microscopy, 2010, 59, 473-479.	0.9	118
115	HAADF-STEM observations of aÎ£13 grain boundary in Î±-Al₂O₃from two orthogonal directions. Philosophical Magazine Letters, 2010, 90, 539-546.	1.2	13
116	Elemental mapping in scanning transmission electron microscopy. Journal of Physics: Conference Series, 2010, 241, 012061.	0.4	11
117	Prospects for 3D imaging of dopant atoms in ceramic interfaces. Journal of Electron Microscopy, 2010, 59, S29-S38.	0.9	4
118	Quantum mechanical model for phonon excitation in electron diffraction and imaging using a Born-Oppenheimer approximation. Physical Review B, 2010, 82, .	3.2	113
119	Standardless Atom Counting in Scanning Transmission Electron Microscopy. Nano Letters, 2010, 10, 4405-4408.	9.1	212
120	Atomic Structure of a CeO₂ Grain Boundary: The Role of Oxygen Vacancies. Nano Letters, 2010, 10, 4668-4672.	9.1	173
121	Model of phonon excitation by fast electrons in a crystal with correlated atomic motion. Physical Review B, 2009, 80, .	3.2	16
122	Quantitative comparisons of contrast in experimental and simulated bright-field scanning transmission electron microscopy images. Physical Review B, 2009, 80, .	3.2	55
123	High-angle scattering of fast electrons from crystals containing heavy elements: Simulation and experiment. Physical Review B, 2009, 79, .	3.2	96
124	Theory of dynamical scattering in near-edge electron energy loss spectroscopy. Physical Review B, 2009, 80, .	3.2	14
125	Atomic-scale imaging of individual dopant atoms in a buried interface. Nature Materials, 2009, 8, 654-658.	27.5	109
126	What atomic resolution annular dark field imaging can tell us about gold nanoparticles on <mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" altimg="si0059.gif" overflow="scroll"><mml:msub><mml:mrow><mml:mi>TiO</mml:mi></mml:mrow><mml:mrow><mml:mn>2</mml:mn></mml:mrow></ (1 1 0). Ultramicroscopy, 2009, 109, 1435-1446.	1.9	8

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127	Robust atomic resolution imaging of light elements using scanning transmission electron microscopy. Applied Physics Letters, 2009, 95, .	3.3	334
128	Interface Structures of Gold Nanoparticles on<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:msub><mml:mi>TiO</mml:mi><mml:mn>2</mml:mn></mml:msub></mml:math>(110). Physical Review Letters, 2009, 102, 136105.	7.8	76
129	Direct Imaging of Dopant Segregation in a Ceramic Grain Boundary. Materia Japan, 2009, 48, 639-639.	0.1	0
130	Prospects for 3D Imaging of Dopant Atoms in Ceramic Materials. Microscopy and Microanalysis, 2009, 15, 44-45.	0.4	0
131	Three-dimensional imaging in double aberration-corrected scanning confocal electron microscopy, Part II: Inelastic scattering. Ultramicroscopy, 2008, 108, 1567-1578.	1.9	47
132	Volcano structure in atomic resolution core-loss images. Ultramicroscopy, 2008, 108, 677-687.	1.9	35
133	Three-dimensional imaging in double aberration-corrected scanning confocal electron microscopy, Part I:. Ultramicroscopy, 2008, 108, 1558-1566.	1.9	60
134	Direct Imaging of Reconstructed Atoms on TiO ₂ (110) Surfaces. Science, 2008, 322, 570-573.	12.6	120
135	Quantitative Atomic Resolution Scanning Transmission Electron Microscopy. Physical Review Letters, 2008, 100, 206101.	7.8	342
136	Atomic number contrast in high angle annular dark field imaging of crystals. Materials Science and Technology, 2008, 24, 660-666.	1.6	7
137	Theoretical interpretation of electron energy-loss spectroscopic images. AIP Conference Proceedings, 2008, , .	0.4	3
138	Contrast Reversal in Atomic-Resolution Chemical Mapping. Physical Review Letters, 2008, 101, 236102.	7.8	41
139	Atomic structure, electronic structure, and defect energetics in<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:mrow><mml:mrow><mml:mo>[</mml:mo><mml:mrow><mml:mn>001</mml:mn></mml:mrow><mml:mo>]</mml:mo></mml:mrow></mml:mrow></mml:math> boundaries of<mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline"><mml:mrow><mml:mrow>. Physical Review B, 2008, 78, .	3.2	98
140	Multiple elastic scattering of core-loss electrons in atomic resolution imaging. Physical Review B, 2008, 77, .	3.2	44
141	Modeling Atomic-Resolution Scanning Transmission Electron Microscopy Images. Microscopy and Microanalysis, 2008, 14, 48-59.	0.4	28
142	Three-dimensional imaging using aberration-corrected scanning transmission and confocal electron microscopy. Journal of Physics: Conference Series, 2008, 126, 012036.	0.4	2
143	Depth sectioning using electron energy loss spectroscopy. Journal of Physics: Conference Series, 2008, 126, 012037.	0.4	1
144	Image contrast in atomic resolution high-angle annular dark-field images. Acta Crystallographica Section A: Foundations and Advances, 2008, 64, C65-C65.	0.3	0

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145	New Approach to Quantitative ADF STEM. , 2008, , 129-130.		0
146	Interpreting atomic-resolution spectroscopic images. Physical Review B, 2007, 76, .	3.2	64
147	Two-Dimensional Mapping of Chemical Information at Atomic Resolution. Physical Review Letters, 2007, 99, 086102.	7.8	239
148	Influence of orientation on the contrast of high-angle annular dark-field images of silicon. Physical Review B, 2007, 76, .	3.2	42
149	Depth sectioning in scanning transmission electron microscopy based on core-loss spectroscopy. Ultramicroscopy, 2007, 108, 17-28.	1.9	43
150	Imaging using inelastically scattered electrons in CTEM and STEM geometry. Ultramicroscopy, 2007, 108, 58-67.	1.9	14
151	Spatial incoherence in phase retrieval based on focus variation. Ultramicroscopy, 2006, 106, 914-924.	1.9	48
152	Modelling high-resolution electron microscopy based on core-loss spectroscopy. Ultramicroscopy, 2006, 106, 1001-1011.	1.9	28
153	Three-dimensional ADF imaging of individual atoms by through-focal series scanning transmission electron microscopy. Ultramicroscopy, 2006, 106, 1062-1068.	1.9	122
154	Channeling effects in high-angular-resolution electron spectroscopy. Physical Review B, 2006, 73, .	3.2	18
155	Modelling imaging based on core-loss spectroscopy in scanning transmission electron microscopy. Ultramicroscopy, 2005, 104, 126-140.	1.9	35
156	Quantitative structure retrieval using scanning transmission electron microscopy. Acta Crystallographica Section A: Foundations and Advances, 2005, 61, 397-404.	0.3	11
157	Letter to the Editor: Limitations to the Measurement of Oxygen Concentrations by HRTEM Imposed by Surface Roughness. Microscopy and Microanalysis, 2005, 11, 111-113.	0.4	3
158	Three-dimensional imaging of individual hafnium atoms inside a semiconductor device. Applied Physics Letters, 2005, 87, 034104.	3.3	206
159	Spectroscopic Imaging of Single Atoms Within a Bulk Solid. Physical Review Letters, 2004, 92, 095502.	7.8	299
160	Lattice-resolution contrast from a focused coherent electron probe. Part I. Ultramicroscopy, 2003, 96, 47-63.	1.9	193
161	Lattice-resolution contrast from a focused coherent electron probe. Part II. Ultramicroscopy, 2003, 96, 65-81.	1.9	81
162	Channelling effects in atomic resolution STEM. Ultramicroscopy, 2003, 96, 299-312.	1.9	58

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163	Atomic-Resolution Electron Energy Loss Spectroscopy Imaging in Aberration Corrected Scanning Transmission Electron Microscopy. Physical Review Letters, 2003, 91, 105503.	7.8	101
164	Atomic-Resolution EELS in Aberration-Corrected STEM. Microscopy and Microanalysis, 2003, 9, 852-853.	0.4	1